

BRIAN
INSTRUMENTS

BRIKON 723-4M/QT

WITH INTELLIGENT SERIES/CATEYE ALIGNMENT SUPPORT

CONFIGURATION WORKSHEET AND PROGRAMMING INSTRUCTIONS

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TEST TABLE LAYOUT

The **BRIKON 723-4M/QT** Tester/Analyzer provides the capability to test commercial configurations of 8", 5 1/4" and 3 1/2" FDD drive styles, including double speed/frequency drives used in **SOFTWARE DUPLICATION** environments. The **TEST TABLES** are preset for the most popular drive configurations along with pass/fail limits, test tracks, etc. as shown below.

CONFIGURATION: SOFTWARE DUPLICATION - INTELLIGENT SERIES
VERSION #: 4123 1122 2025 2026 1309

TABLE	DRIVE TYPE						
	SIZE INCHES	SPEED RPM	DATA RATE KBS	TRACKS	HEADS	UNFORMATTED CAPACITY	GENERIC TERM
00	5 1/4	720	1000	80	2	1.6 MB	2XSDS1.2M
01	5 1/4	300	250	40	2	0.5 MB	XT360K
02	5 1/4	300	250	80	2	1.0 MB	XT720K
03	5 1/4	360	500	80	2	1.6 MB	AT1.2MEG
04	3 1/2	300	250	80	2	1.0 MB	XT720K
05	3 1/2	300	500	80	2	2.0 MB	1.4MEG
06	3 1/2	600	500	80	2	1.0 MB	HYPER720K
07	3 1/2	300	1000	80	2	4.0 MB	4MEG
08	5 1/4	180	500	80	2	3.2 MB	STD
09	3 1/2	720	1000	80	2	1.2 MB	2XSDS/1.2M
10	5 1/4	600	500	40	2	0.5 MB	2XSDS/360K
11	5 1/4	600	500	80	2	1.0 MB	2XSDS/720K
12	5 1/4	360	500	80	2	1.6 MB	1XSDS/1.2M
13	5 1/4	600	833	80	2	1.6 MB	1.7XSDS/1.2M
14	3 1/2	600	500	80	2	1.0 MB	2XSDS/720K
15	3 1/2	300	500	80	2	2.0 MB	1XSDS/1.4M
16	3 1/2	600	1000	80	2	2.0 MB	2XSDS/1.4M
17	3 1/2	300	1000	80	2	4.0 MB	1XSDS/2.8M
18	3 1/2	360	500	80	2	1.6 MB	AT/1.2MEG
19	3 1/2	300	1000	80	2	4.0 MB	4MEG SONY

For Configuration details, please refer to the attached **CONFIGURATION WORKSHEET AND PROGRAMMING INSTRUCTIONS** where all parameters for each **PARAMETER TABLE** are defined.

PROGRAMMING INFORMATION

The **BRIKON 723-4M/QT** has 20 **TEST TABLES** that may be altered by the user. This is done by modifying **EPROM** memory locations as shown in the attached **DRIVE CONFIGURATION MAP**. All alterable locations are stored in the **EPROM (27256)** located on the **Z-80 Board**.

When making temporary changes, using the **RAM** function, the **RAM** location for the particular parameter to be modified is also included as part of the address information provided. The **DRIVE CONFIGURATION MAP** defines the **EPROM** and **RAM** locations of each modifiable parameter along with additional notes, if required.

ALL LOCATIONS ARE IN HEXADECIMAL. ALL VALUES IN THESE LOCATIONS ARE PRESENTED AND ENTERED IN HEXADECIMAL. ALL TWO BYTE PARAMETERS ARE ENTERED LSB FIRST.

PROGRAMMING NOTES

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NOTE 1

There are 20 TEST TABLES and are numbered 00H - 13H. The value in this location determines the TEST TABLE blinking in the Display when tester power is applied.

NOTE 2

If 01H is specified only Head 0 is tested. If 02H is specified, Head 0 is tested first, followed by Head 1. If 04H is specified, only Head 1 is tested.

NOTE 3

This parameter is used to establish both the combinations of RPM/DATA RATE and INTERFACE PROTOCOL/RPM, which are used by the tester for timing and control. The most significant half byte selects a sub-table based on the combination of RPM/DATA RATE as follows:

<u>HEX VALUE</u>	<u>RPM</u>	<u>BIT RATE</u>
0	360	500 KBS
1	600	500 KBS
2	300	250 KBS
3	300	500 KBS
4	300	1000 KBS
5	180	500 KBS
6	600	1000 KBS
7	600	833 KBS
8	720	1000 KBS
9-F	RESERVED	

The least significant half byte selects a sub-table based on the combination of INTERFACE PROTOCOL/RPM as follows:

<u>HEX VALUE</u>	<u>DRIVE TYPE</u>	<u>RPM</u>
0	8", 5 1/4"	360
1	5 1/4"	300
2	5 1/4, 3 1/2"	600
3	3 1/2"	300
4	5 1/4"	180
5	5 1/4"	720
6	3 1/2"	720
7	3 1/2"	360
8-F	RESERVED	

PROGRAMMING NOTES (Cont'd)

NOTE 4

This parameter is used to control the individual Select lines. When set to **0FH**, all Select lines are active. When set to **00H**, no Select lines are active. Use the following as a guide:

<u>BIT</u>	<u>DRIVE SELECT LINE</u>
0	DS 0
1	DS 1
2	DS 2
3	DS 3

NOTE 5

This single byte parameter is used to establish the preset condition of the upper eight functions in the **CONFIGURATION** Row as follows:

<u>BIT</u>	<u>FUNCTION</u>
7	If 1, USER DATA 15 BYTES is ON and used in place of Random Data in the WRITE/READ TEST , and in place of DB,6D,B6 in WINDOW MARGIN . If 0, USER DATA 15 BYTES is OFF and not used.
6	If 1, STOP AFTER ONE PASS is ON. If 0, it is OFF.
5	If 1, STOP ON ERROR is ON. If 0, it is OFF.
4	If 1, TEST ALL TRACKS is ON. If 0, TEST ONE TRACK is ON.
3	If 1, TEST ONE TRACK is ON. If 0, TEST ALL TRACKS is ON.
2	RESERVED
1	RESERVED
0	RESERVED

NOTE 6

This byte controls monitoring of the D.C. output voltages for the drive. If the Bit is 1 the voltage is monitored, otherwise it is not. The Bits are assigned as follows:

<u>BIT</u>	<u>VOLTAGE</u>
0	+12 VDC
1	+ 5 VDC
2	- 5 VDC
3	+24 VDC
4-7	RESERVED

NOTE 7

Each of the eight bits of this byte control the corresponding Port of operation used with the **MULTI- PLEXER**. If the Bit is 1 the Port is active, if 0, it is inactive. Two examples follow.

- FF is Binary 1111 1111: All Ports are active.
- AA is Binary 1010 1010: Ports 1,3,5,7 are active; Ports 0,2,4,6 are inactive.

PROGRAMMING NOTES (Cont'd)

NOTE 8

The Bits of this byte control configuration parameters as follows.

Bits 7 6

0 0: Data Rate is **500KBS**

0 1: Data Rate is **1000KBS**

1 0: Data Rate is **250KBS**

1 1: Data Rate is **833KBS**

Bit 5: **R E S E R V E D**

Bit 4: If **0**, do normal **READ TEST**. If **1**, do every 4th track (abbreviated style)

Bit 3: If **1**, do Apple 5 1/4". Otherwise do not.

Bit 2: If **0**, do **MOTOR ON** at Pin 16 of 34 pin cable. If **1**, do **LO I** at Pin 2 of 50 pin cable.

Bit 1: If **0**, do head unload by turning Off pin 18 of the 50 pin cable; if **1** do head unload by turning **OFF** all Select lines.

Bit 0: If **1** do **INDEX TO DATA** for a single Index (5.25 and 3.5 inch drives). If **0** do **INDEX TO DATA** for 2 Indexes (8 inch drives).

NOTE 9

These parameter values are used to control how many passes of each Test are performed during the two Auto Tests provided by the Tester. The lower half byte controls the number performed during **AUTO SYSTEM TEST** and the upper half byte controls the number performed during **AUTO ALIGN TEST**. Each parameter may be set from **0-15**. If set to **0**, the Test will not be performed. Regardless of the setting, the individual Test is available via the Front Panel Keys.

NOTE 10

The functions **STEP TIME NOM./MAX./MIN.** and **INDEX PERIOD/PULSE WIDTH** are in *tenths of milliseconds*. A decimal value of 400 (0190 Hex) will result in a step time of 40.0 milliseconds. The two bytes are stored least significant byte first.

NOTE 11

Both clock and data margin limits may be specified. The data pattern normally used will not generate clock pulses in MFM. **FFFF** can be used in the clock margin locations to cause the tester to verify that there are no clocks; in this case if there are clocks, the test will fail.

NOTE 12

This byte defines which combination of sub-tests are performed by the **WRITE/READ** Test. If a Bit is **1**, the subtest is performed. If the Bit is **0**, it is not. The bits are defined as follows:

<u>BIT</u>	<u>SUBTEST</u>
7	MFM-2
6	MFM-1
5	RESERVED
4	RESERVED
3	RESERVED
2	RESERVED
1	RESERVED
0	RESERVED

PROGRAMMING NOTES (Cont'd)

NOTE 13

The Bits of this byte control printing as follows:

<u>BIT</u>	<u>FUNCTION</u>
0	If 1, test results are printed. If 0, they are not.
1	If 1, a P or F is printed at the front of all tests. If 0, the position is blank for Passing tests. An F is always printed for Failing tests.
2	If 0, exit both AUTO SYSTEM and AUTO ALIGN with <i>Form Feed</i> . If 1, exit with <i>3 Line Feeds</i> .
3	If 1, the test summary is printed. If 0, it is not.

NOTE 14

These parameter values are used to control how many passes of each Test are performed during the two Auto Tests provided by the Tester. The lower half byte controls the number performed during **AUTO SYSTEM TEST** and the upper half byte controls the number performed during **AUTO ALIGN TEST**. Each parameter may be set from 0-15. If set to 0, the Test will not be performed. Regardless of the setting, the individual Test is available via the Front Panel Keys.

NOTE 15

This track number is the higher of the two tracks between which the TRACK 00 SENSOR must change states. It is in the most significant half of the byte. The least significant half byte is the table number.

NOTE 16

There are up to three tracks on which **INDEX TO DATA** may be measured. If less than three tracks are desired, then use **FFH** instead of a track number to skip that track.

NOTE 17

In the **STEP SETTLE** and **HEAD LOAD SETTLE** Tests a track is written with a uniform pattern and the head is then stepped away, or is unloaded. Then at index the head is stepped back to the track, or is loaded. The amplitude of the head signal is sampled at intervals of 0.5 mS. and the values are saved. Then on a subsequent revolution samples are taken at the same times with respect to index. The two sets of samples are compared. The sample time at which all subsequent samples taken during settling differ from the corresponding samples taken after settling by no more than X percent is the Settling Time, and X is the value in this byte. The value used is generally a percentage difference of 5 to 20 percent.

NOTE 18

These values are the allowable percentage difference of the time of changing of the Track 00 Sensor as compared to a time of change that is half way between the two tracks. Positive and negative values are allowed and are entered as 8-bit 2's-complement numbers. Negative numbers are calculated by subtracting the magnitude of the number from 256 and converting to hex. The range is +/- 99%.

NOTE 19

This function is used in conjunction with the Multiplexer and controls whether the Multiplexer stops after a pass of all the activated ports or not. If set to **00H**, the Multiplexer will continuously advance to the next port (after the highest port is finished, the lowest port will start again). If set to **01H**, the Multiplexer will stop after the highest activated port is complete.

PROGRAMMING NOTES (Cont'd)

NOTE 20

This parameter is used to preset the UART controls for PARITY, NUMBER OF BITS, and BAUD RATE. The construction of the byte is as follows:

Bits	<u>7 6 5</u>	<u>FUNCTION</u>
	0 0 0	Even Parity.
	0 0 1	Odd Parity.
	0 1 0	Parity Bit = 0.
	0 1 1	Parity Bit = 1.
Bit 4		If 0, do 7 DATA BITS. If 1, do 8 DATA BITS.
Bits	<u>3 2 1 0</u>	
	0 1 0 0	300 BAUD
	0 1 1 0	1200 BAUD
	1 0 1 1	9600 BAUD
	1 1 0 0	19200 BAUD

NOTE 21

This parameter is used to select the width of the target Head when using the INTELLIGENT SERIES Alignment Diskettes. Because the Tester presents the results in uM., it is necessary to know the target Head width to accurately present offtrack values. The value in this parameter is *one half* of the target Head width (plus/minus from center) in *micrometers*.

NOTE 22

This function is used to preset the style of alignment to be used. A choice of three styles are available. When set to 1, the INTELLIGENT SERIES is active, requiring the INTELLIGENT SERIES diskettes to be used for STATIC TRACK ALIGN, OPTALIGN, and AZIMUTH measurements. When set to 0, the *cateye* measuring method is active, requiring a *traditional cateye* type diskette. When set to 2, the *SONY ED cateye* is active, requiring the Sony Model RZW 406D alignment diskette. Some Tests in the AUTO ALIGN sequence, such as WINDOW MARGIN, ASYMMETRY, and AMPLITUDE do not produce meaningful results when in either of the *cateye* modes and must be considered. The background CONVERT - KEY C is used to correlate between diskette styles as follows.

INTELLIGENT SERIES - Begin in this mode and CONVERT to *traditional cateye* mode.

TRADITIONAL CATEYE - Begin in this mode and CONVERT to INTELLIGENT SERIES mode.

SONY ED CATEYE - Begin in this mode and CONVERT to INTELLIGENT SERIES mode.

PROGRAMMING NOTES (Cont'd)

NOTE 23

These functions are used to control the conditions of the graphics output when performing **WINDOW MARGIN** or **ASYMMETRY** Tests. The graphic output provides measurement distribution for each Head.

The Parameter **GRAPH OUT BY TOTAL SAMPLES** is used to cause the graph to output after a certain number of total samples have accrued. The range of setting is from **1-255**. If set to **1**, the graph outputs after each **WINDOW MARGIN** or **ASYMMETRY** Test. If set to **255**, the graph outputs after 255 Tests have been performed.

The Parameter **GRAPH OUT BY INDIVIDUAL SAMPLE** is used to cause the graph to output after a certain number repeating measurement values have accrued. The range of setting is from **1-255**. If set to **1**, the graph outputs after each **WINDOW MARGIN** or **ASYMMETRY** Test. If set to **255**, the graph outputs after 255 of the same value has accrued or the Parameter **GRAPH OUT BY TOTAL SAMPLES** is reached, whichever occurs first.

The Parameter **GRAPH ON/OFF** controls whether the graph is printed. If set to **0**, the graph is **OFF**. If set to **1**, the graph is **ON**. If it is desired to produce the graph without the individual sample values, set the **GRAPH ON/OFF** parameter to **1** and use the **PRINT ON/OFF** function (Key **B**) to turn the printer Off during the measurements. In this manner, the individual measurements are not printed while outputting the graph after each accumulation.

If the Parameters **GRAPH OUT BY TOTAL SAMPLES** and **GRAPH OUT BY INDIVIDUAL SAMPLE** are set to **0**, the graph is output after **256** Tests have been performed.

This capability is invoked only when the Parameter **STOP AFTER ONE PASS** is **OFF**.

NOTE 24

There are individual pass/fail limits for **ALIGNMENT**, **OPTALIGN**, and **AZIMUTH** measurements for both *catye* and **INTELLIGENT SERIES** diskettes. Because they present measurement information in different terms, caution must be exercised when setting these limits.

ALIGNMENT HIGH/OPTALIGN HIGH - When in the **INTELLIGENT SERIES** Mode, alignment error information is in *micrometers*. When in the *catye* Mode, alignment error information is in *percentage*.

AZIMUTH - When in the **INTELLIGENT SERIES** Mode, Azimuth error information is presented in *minutes*. When in the *catye* Mode, the information is presented in *burst ratio*. When in the **Sony RZW406D** Mode, Azimuth error information is presented in *minutes*.

The Tester selects the pass/fail limit based on the current Mode of the Tester. This includes the **ALIGN MODE** Parameter and the state of the **CHANGE ALIGN TYPE** function in the **AUXILIARY** Row.

PROGRAMMING NOTES (Cont'd)

NOTE 25

This byte controls both the number of times it may be performed during **AUTO ALIGN** and the method of **MULTITRACK** Testing.

The upper half byte is used to control the number of times performed during **AUTO ALIGN**. The range of setting is **0-15**. Caution should be observed to consider the Parameter **NUMBER OF OPTALIGN/HYSTERESIS TESTS**. These are mutually exclusive Tests and each will independently decrement the meter. For inspection environments, it is usually only required to perform **MULTITRACK ALIGN** or **OPTALIGN/HYSTERESIS**, but not both. Multitrack Testing provides more information. Single Track Testing uses a less expensive diskette.

<u>HEX VALUE</u>	<u>FUNCTION</u>
0-F	If 0, skip the Test. Any other value is the number of times.

The lower half byte is constructed to provide control of the method of testing as follows.

<u>HEX VALUE</u>	<u>FUNCTION</u>
0	Perform in BOTH directions
1	Perform FROM IN direction only
2	Perform FROM OUT direction only
3	Perform in BOTH directions
4-F	R E S E R V E D

PARAMETER	--DRIVE CONFIGURATION--									
	TB00	TB01	TB02	TB03	TB04	TB05	TB06	TB07	TB08	TB09
NUMBER OF HEADS	2	2	2	2	2	2	2	2	2	2
NUMBER OF TRACKS	80	40	80	80	80	80	80	80	80	80
DRIVE TYPE	85H	21H	21H	00H	23H	33H	12H	43H	54H	86H
NOMINAL STEP RATE	3.0	6.0	3.0	3.0	3.0	3.0	6.0	3.0	3.0	3.0
MAXIMUM STEP RATE	4.0	7.0	4.0	4.0	4.0	4.0	7.0	4.0	4.0	4.0
MINIMUM STEP RATE	3.0	6.0	3.0	3.0	3.0	3.0	6.0	3.0	3.0	3.0
DRIVE SELECT	03H	03H	03H	03H	03H	03H	03H	03H	03H	03H
TEST CONTROL BYTE	50H	50H	50H	50H	50H	50H	50H	50H	50H	50H
POWER CONTROL	03H	03H	03H	03H	03H	03H	03H	03H	03H	03H
MUX CONTROL	00H	00H	00H	00H	00H	00H	00H	00H	00H	00H
PRINTER OUTPUT CONTROL	0FH	0FH	0FH	0FH	0FH	0FH	0FH	0FH	0FH	0FH
CONFIGURATION BYTE	43H	83H	83H	03H	83H	03H	23H	43H	03H	43H
ALIGN MODE	01H	01H	01H	01H	01H	01H	01H	01H	00H	00H
MEDIA MODEL	00/CAT	01/CAT	02/CAT	03/CAT	04/CAT	05/CAT	14/CAT	07/CAT	CAT	CAT

	--SYSTEM TESTS--									
	TB00	TB01	TB02	TB03	TB04	TB05	TB06	TB07	TB08	TB09
# OF INDEX TESTS	13H	13H	13H	13H	13H	13H	13H	13H	13H	13H
# OF WINDOW MARGIN TESTS	33H	33H	33H	33H	33H	33H	33H	33H	03H	03H
# OF ASYMMETRY TESTS	33H	33H	33H	33H	33H	33H	33H	33H	03H	03H
# OF WRITE/READ TESTS	01H	01H	01H	01H	01H	01H	01H	01H	01H	01H
# OF STEP TESTS	01H	01H	01H	01H	01H	01H	01H	01H	01H	01H
# OF READ TESTS	01H	01H	01H	01H	01H	01H	01H	01H	01H	01H
INDEX PERIOD LOW	82.5	195.0	195.0	162.5	195.0	195.0	97.5	195.0	328.3	82.5
INDEX PERIOD HIGH	84.5	205.0	205.0	170.9	205.0	205.0	102.5	205.0	338.1	84.5
INDEX PULSE WIDTH LOW	0.1	1.0	1.0	1.0	0.1	0.1	0.1	0.1	0.1	0.1
INDEX PULSE WIDTH HIGH	8.0	8.0	8.0	8.0	8.0	8.0	8.0	8.0	15.0	8.0
DATA MARGIN LOW	300	500	500	250	500	250	250	200	250	300
CLOCK MARGIN LOW	FFFFH	FFFFH	FFFFH	FFFFH	FFFFH	FFFFH	FFFFH	FFFFH	FFFFH	FFFFH
ASYMMETRY HIGH	120	600	600	300	600	300	300	200	250	120
W/R SUBTEST CONTROL	COH	COH	COH	COH	COH	COH	COH	COH	COH	COH
READ RETRIES + 1	2	2	2	2	2	2	2	2	2	2

	--ALIGNMENT TESTS--									
	TB00	TB01	TB02	TB03	TB04	TB05	TB06	TB07	TB08	TB09
# OF ECCENTRICITY TESTS	10H	10H	10H	10H	10H	10H	10H	10H	00H	00H
# OF OPTALIGN HYSTERESIS TESTS	30H	30H	30H	30H	30H	30H	30H	30H	30H	30H
# OF INDEX TO DATA TESTS	20H	20H	20H	20H	20H	20H	20H	20H	20H	20H
# OF AZIMUTH TESTS	10H	10H	10H	10H	10H	10H	10H	10H	10H	10H
# OF RESOLUTION TESTS	10H	10H	10H	10H	10H	10H	10H	10H	00H	00H
# OF STEP SETTLE TIME TESTS	10H	10H	10H	10H	10H	10H	10H	10H	10H	10H
# OF HEAD LOAD SETTLE TESTS	00H	00H	00H	00H	00H	00H	00H	00H	00H	00H
# OF TRACK 00 SENSOR TESTS	00H	00H	00H	00H	00H	00H	00H	00H	00H	00H
# HEAD AMPLITUDE TESTS	10H	10H	10H	10H	10H	10H	10H	10H	00H	00H
ECCENTRICITY TRACK	10	10	10	10	10	10	10	10	10	10
ALIGNMENT TRACK	32	16	32	32	40	40	40	40	32	40
OPTALIGN OFFSET TRACKS	5	5	5	5	5	5	5	5	5	5
AZIMUTH TRACK	68	34	68	68	40	40	40	40	68	40
RESOLUTION TRACK FOR 1F	64	32	64	64	75	75	75	75	64	75
RESOLUTION TRACK FOR 2F	64	32	64	64	75	75	75	75	64	75
HEAD SETTLE TRACK	64	32	64	64	75	75	75	75	64	75
INDEX TO DATA TRACK A	2	1	2	2	2	2	2	2	2	2
INDEX TO DATA TRACK B	32	16	32	32	40	40	40	40	FFH	40
INDEX TO DATA TRACK C	68	34	68	68	69	69	69	69	68	69
INDEX TO DATA HIGH	300	300	300	300	900	900	900	900	600	300
INDEX TO DATA LOW	100	100	100	100	50	50	50	50	200	50
AZIMUTH HIGH - INTELLIGENT	9	12	18	18	30	21	30	9	18	9
RESOLUTION LOW	60	60	60	60	60	60	60	55	55	60
STEP SETTLE HIGH	20	20	20	20	20	20	20	20	20	18
HEAD LOAD HIGH	60	40	40	40	60	60	60	60	60	60
STEP SETTLE THRESHOLD	20	20	20	20	20	20	20	20	20	20
AMPLITUDE LOW	100	150	150	150	150	100	100	100	150	100
MOTOR START HIGH	750	500	500	500	500	500	500	500	500	750
ECCENTRICITY HIGH	20	20	20	20	20	20	20	20	20	20
COMPLIANCE HIGH	20	20	20	20	20	20	20	20	20	20
ALIGNMENT HIGH - INTELLIGENT	11	42	21	21	17	17	17	17	21	09
TRK 00 FROM TRACK	3	2	2	2	1	1	1	1	2	1
TRK 00 SENSOR LOW LIMIT	-85	-50	-50	-50	-50	-50	-50	-50	-50	-50
TRK 00 SENSOR HIGH LIMIT	+85	+50	+50	+50	+50	+50	+50	+50	+50	+50
OPTALIGN HIGH - INTELLIGENT	11	42	21	21	17	17	17	17	21	09
ERASE LIMIT	5	5	5	5	5	5	5	5	5	5
HEAD WIDTH/2	84	168	84	84	69	69	69	69	84	69
AZIMUTH HIGH CATEYE	100	100	100	100	100	100	100	100	100	100
ALIGNMENT HIGH CATEYE	10	25	25	25	25	25	25	25	25	10
OPTALIGN HIGH CATEYE	10	25	25	25	25	25	25	25	25	10
# MULTITRACK/CONTROL	02H	00H	00H	00H	00H	00H	00H	00H	00H	00H
RESERVED 2	0	0	0	0	0	0	0	0	0	0

TEST TABLE AT POWER UP 16 ONE PASS MUX 0 UART PRESET 2BH HUMIDITY PRESET 50
 GRAPH BY TOTAL 255 GRAPH BY SAMPLE 255 GRAPH ON/OFF 01

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